## **EcoSPARK® 2 Ignition IGBT**

## 300 mJ, 500 V, N-Channel Ignition IGBT

#### **Features**

- SCIS Energy = 300 mJ at  $T_J = 25$ °C
- Logic Level Gate Drive
- AEC-Q101 Qualified and PPAP Capable
- These Device is Pb-Free and are RoHS Compliant

#### **Applications**

- Automotive Ignition Coil Driver Circuits
- High Current Ignition System
- Coil on Plug Application

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
BV <sub>CER</sub>	Collector to Emitter Breakdown Voltage (I <sub>C</sub> = 1 mA)	500	V
BV <sub>ECS</sub>	Emitter to Collector Voltage – Reverse Battery Condition (I <sub>C</sub> = 10 mA)	20	٧
E <sub>SCIS25</sub>	Self Clamping Inductive Switching Energy (Note 1)	300	mJ
E <sub>SCIS150</sub>	Self Clamping Inductive Switching Energy (Note 2)	180	mJ
I <sub>C25</sub>	Collector Current Continuous at $V_{GE} = 4.0 \text{ V}$ , $T_C = 25^{\circ}\text{C}$	32	Α
I <sub>C110</sub>	Collector Current Continuous at V <sub>GE</sub> = 4.0 V, T <sub>C</sub> = 110°C	27	Α
$V_{GEM}$	Gate to Emitter Voltage Continuous	±10	V
P <sub>D</sub>	Power Dissipation Total, T <sub>C</sub> = 25°C	150	W
	Power Dissipation Derating, for T <sub>C</sub> > 25°C	1.1	W/°C
$T_J$	Operating Junction Temperature Range	-40 to +175	°C
T <sub>STG</sub>	Storage Junction Temperature Range	-40 to +175	°C
$T_L$	Max. Lead Temperature for Soldering (Leads at 1.6 mm from case for 10 s)	300	ç
T <sub>PKG</sub>	Max. Lead Temperature for Soldering (Package Body for 10 s)	260	°C
ESD	Electrostatic Discharge Voltage at 100 pF, 1500 $\Omega$	4	kV

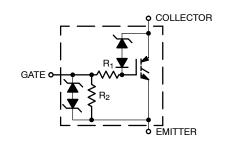
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Self clamped inductive Switching Energy (ESCIS25) of 335 mJ is based on the test conditions that is starting  $T_J = 25^{\circ}C$ , L = 3 mHy, ISCIS = 14.2 A,  $R_{GE} = 1$  k $\Omega$ , VCC = 100 V during inductor charging and VCC = 0 V during time in clamp.
- 2. Self Clamped inductive Switching Energy (ESCIS150) of 180 mJ is based on the test conditions that is starting  $T_J=150^{\circ}C$ , L = 3mHy, ISCIS = 11 A,  $R_{GE}=1~k\Omega, VCC$  = 100 V during inductor charging and VCC = 0 V during time in clamp.



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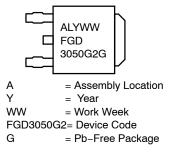
#### www.onsemi.com





DPAK (SINGLE GAUGE) CASE 369C

#### **MARKING DIAGRAM**



#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

#### THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Units
Junction-to-Case - Steady State (Drain)		0.9	°C/W

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Test C	Conditions	Min	Тур.	Max.	Units
FF CHARA	ACTERISTICS			•			
BV <sub>CER</sub>	Collector to Emitter Breakdown Voltage	$I_{CE}$ = 2 mA, $V_{GE}$ $R_{GE}$ = 1 k $\Omega$ , $T_{J}$ =	= 0 V, = -40 to 150°C	470	-	530	V
BV <sub>CES</sub>	Collector to Emitter Breakdown Voltage	I <sub>CE</sub> = 10 mA, V <sub>G</sub> R <sub>GE</sub> = 0, T <sub>J</sub> = -4	E = 0 V, 40 to 150°C	495	-	555	٧
BV <sub>ECS</sub>	Emitter to Collector Breakdown Voltage	$I_{CE} = -75 \text{ mA}, V_0$ $T_J = 25^{\circ}\text{C}$	<sub>GE</sub> = 0 V,	20	_	-	٧
BV <sub>GES</sub>	Gate to Emitter Breakdown Voltage	I <sub>GES</sub> = ±5 mA		±12	±14	-	V
I <sub>CER</sub>	Collector to Emitter Leakage Current	V <sub>CE</sub> = 250 V	T <sub>J</sub> = 25°C	-	-	25	μΑ
		$R_{GE} = 1 k\Omega$	T <sub>J</sub> = 150°C	-	-	1	mA
I <sub>ECS</sub>	Emitter to Collector Leakage Current	V <sub>EC</sub> = 15 V	T <sub>J</sub> = 25°C	-	-	1	mA
			T <sub>J</sub> = 150°C	-	-	40	
R <sub>1</sub>	Series Gate Resistance			-	111	-	Ω
R <sub>2</sub>	Gate to Emitter Resistance			10K	-	30K	Ω
N CHARA	CTERISTICS (Note 5)			•			
V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage	I <sub>CE</sub> = 6 A, V <sub>GE</sub> = 4 V, T <sub>J</sub> = 25°C		-	1.1	1.2	V
V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage	I <sub>CE</sub> = 10 A, V <sub>GE</sub> = 4.5 V, T <sub>J</sub> = 150°C		-	1.3	1.45	V
V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage	I <sub>CE</sub> = 15 A, V <sub>GE</sub>	= 4.5 V, T <sub>J</sub> = 150°C	-	1.6	1.75	V
YNAMIC C	HARACTERISTICS	•			•	•	
Q <sub>G(ON)</sub>	Gate Charge	I <sub>CE</sub> = 10 A, V <sub>CE</sub>	= 12 V, V <sub>GE</sub> = 5 V	-	22	-	nC
V <sub>GE(TH)</sub>	Gate to Emitter Threshold Voltage	I <sub>CE</sub> = 1 mA	T <sub>J</sub> = 25°C	1.3	1.6	2.2	V
		$V_{CE} = V_{GE}$ $T_{J} = 150^{\circ}C$	T <sub>J</sub> = 150°C	0.75	1.1	1.8	
$V_{GEP}$	Gate to Emitter Plateau Voltage	V <sub>CE</sub> = 12 V, I <sub>CE</sub> = 10 A		-	2.7	-	V
WITCHING	CHARACTERISTICS						
td <sub>(ON)R</sub>	Current Turn-On Delay Time-Resistive	$V_{CE}$ = 14 V, $R_L$ = 1 $\Omega$ , $V_{GE}$ = 5 V, $R_G$ = 1 K $\Omega$ ,		_	0.9	4	μs
t <sub>rR</sub>	Current Rise Time-Resistive			_	1.6	7	
td <sub>(OFF)L</sub>	Current Turn-Off Delay Time-Inductive	$V_{CE}$ = 300 V, L = 2 mH, $V_{GE}$ = 5 V, $R_{G}$ = 1 K $\Omega$ ,		-	5.4	15	1
t <sub>fL</sub>	Current Fall Time-Inductive	1		-	1.4	15	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Reel Diameter	Tape Width	Qty <sup>†</sup>
FGD3050G2	FGD3050G2V	DPAK (Pb-Free)	330 mm	16 mm	2500

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### TYPICAL CHARACTERISTICS

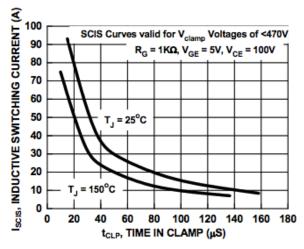


Figure 1. Self Clamped Inductive Switching Current vs. Time in Clamp

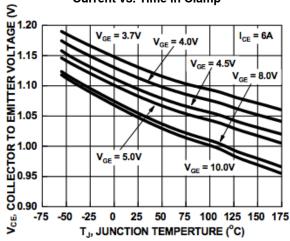


Figure 3. Collector to Emitter On-State Voltage vs. Junction Temperature

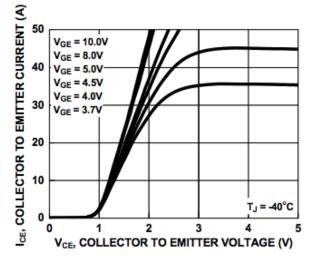


Figure 5. Collector to Emitter On-State Voltage vs. Collector Current

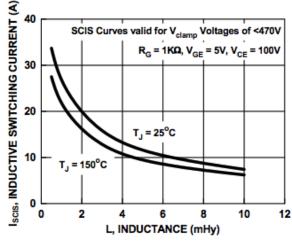


Figure 2. Self Clamped Inductive Switching Current vs. Inductance

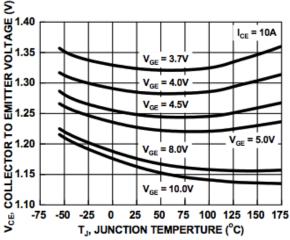


Figure 4. Collector to Emitter On-State Voltage vs. Junction Temperature

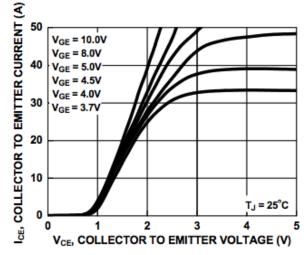


Figure 6. Collector to Emitter On-State Voltage vs. Collector Current

#### TYPICAL CHARACTERISTICS (continued)

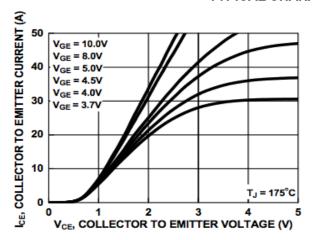


Figure 7. Collector to Emitter On-State Voltage vs.
Collector Current

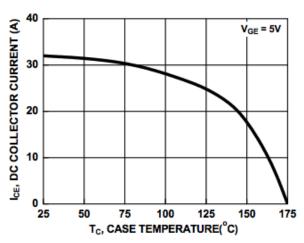


Figure 9. DC Collector Current vs. Case Temperature

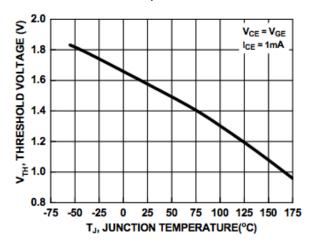


Figure 11. Threshold Voltage vs. Junction Temperature

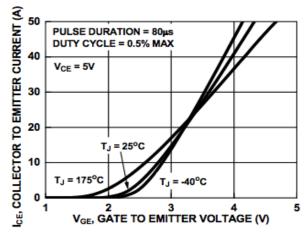


Figure 8. Transfer Characteristics

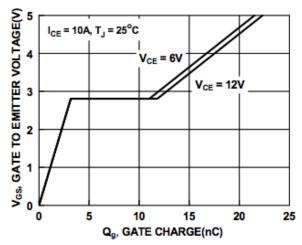


Figure 10. Gate Charge

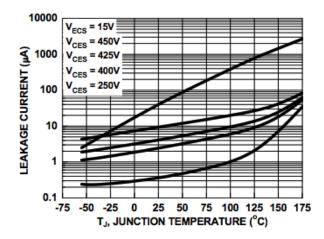
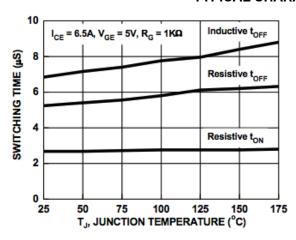


Figure 12. Leakage Current vs. Junction Temperature Temperature

#### TYPICAL CHARACTERISTICS (continued)



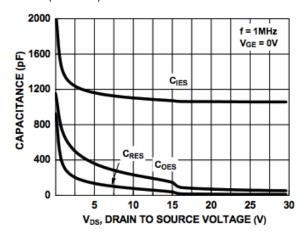


Figure 13. Switching Time vs. Junction Temperature

Figure 14. Capacitance vs. Collector to Emitter Voltage

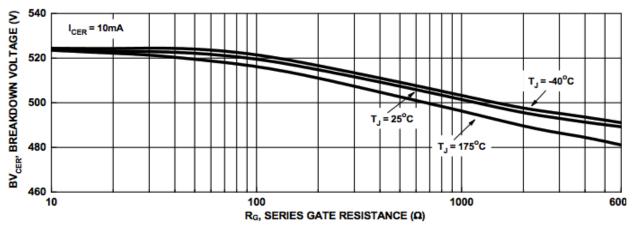


Figure 15. Break down Voltage vs. Series Resistance

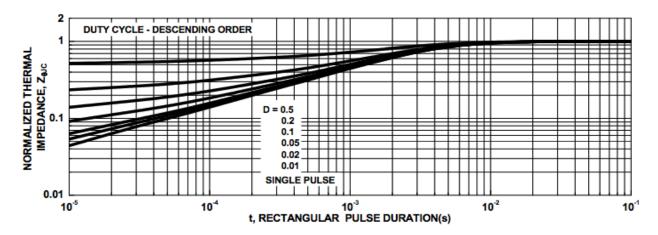
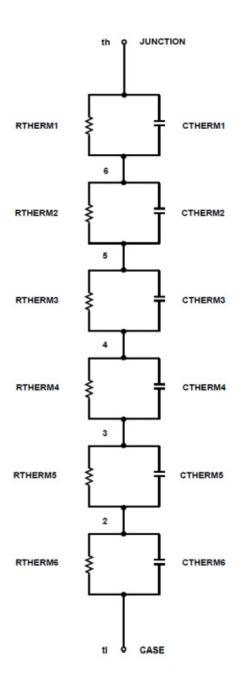


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

#### **SPICE Thermal Model**

CTHERM1	th 6	5.7337E-05
CTHERM2	6 5	5.3736E-03
CTHERM3	5 4	1.1141E-03
CTHERM4	4 3	2.8690E-04
CTHERM5	3 2	7.4429E-04
CTHERM6	2 tl	3.7019E-03
RTHERM1	th 6	6.6403E-03
RTHERM2	6 5	5.8449E-01
RTHERM3	5 4	5.3930E-02
RTHERM4	4 3	9.2492E-03
RTHERM5	3 2	1.5794E-02
RTHERM6		



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**A1** 

**DETAIL A** ROTATED 90° CW

#### **DPAK (SINGLE GAUGE)** CASE 369C

**BOTTOM VIEW** 

ALTERNATE CONSTRUCTIONS

**DATE 21 JUL 2015** 

- IOTES. 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: INCHES. 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-

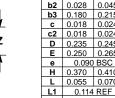
- MENSIONS b3, L3 and Z.

  Jimensions b And E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.

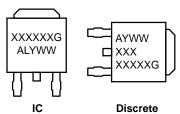
  MENSIONS D AND E ARE DETERMINED AT THE
- OUTERMOST EXTREMES OF THE PLASTIC BODY.

  6. DATUMS A AND B ARE DETERMINED AT DATUM
- 7. OPTIONAL MOLD FEATURE.

	INCHES		MILLIM	ETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.028	0.045	0.72	1.14
b3	0.180	0.215	4.57	5.46
С	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29 BSC	
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.114	REF	2.90	REF
L2	0.020	BSC	0.51 BSC	
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	



#### **GENERIC MARKING DIAGRAM\***

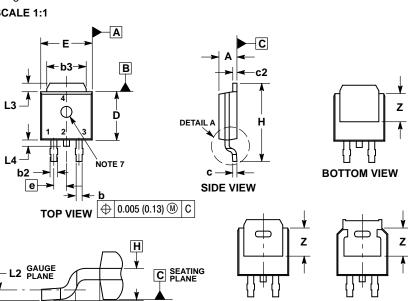


XXXXXX = Device Code

= Assembly Location Α = Wafer Lot L Υ = Year = Work Week WW G = Pb-Free Package

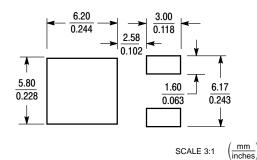
\*This information is generic. Please refer to device data sheet for actual part marking.

# ISSUE F



STYLE 1: PIN 1. BASE 2. COLLE 3. EMITTI 4. COLLE	ER 3.		STYLE 3: PIN 1. ANODI 2. CATHO 3. ANODI 4. CATHO	E DDE E	TYLE 4: PIN 1. CATHODE 2. ANODE 3. GATE 4. ANODE	STYLE 5: PIN 1. GATE 2. ANODE 3. CATHODE 4. ANODE
STYLE 6: PIN 1. MT1 2. MT2 3. GATE 4. MT2	STYLE 7: PIN 1. GATE 2. COLLEC 3. EMITTER 4. COLLEC	TOR 2	E 8: 1. N/C 2. CATHODE 3. ANODE 4. CATHODE	3. F		STYLE 10: PIN 1. CATHODE 2. ANODE T 3. CATHODE 4. ANODE

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	DPAK SINGLE GAUGE SURFACE MOUNT		PAGE 1 OF 2



<b>DOCUMENT</b>	NUMBER:
98AON10527	7D

PAGE 2 OF 2

ISSUE	REVISION	DATE
0	RELEASED FOR PRODUCTION. REQ. BY L. GAN	24 SEP 2001
А	ADDED STYLE 8. REQ. BY S. ALLEN.	06 AUG 2008
В	ADDED STYLE 9. REQ. BY D. WARNER.	16 JAN 2009
С	ADDED STYLE 10. REQ. BY S. ALLEN.	09 JUN 2009
D	RELABELED DRAWING TO JEDEC STANDARDS. ADDED SIDE VIEW DETAIL A. CORRECTED MARKING INFORMATION. REQ. BY D. TRUHITTE.	29 JUN 2010
E	ADDED ALTERNATE CONSTRUCTION BOTTOM VIEW. MODIFIED DIMENSIONS b2 AND L1. CORRECTED MARKING DIAGRAM FOR DISCRETE. REQ. BY I. CAMBALIZA.	06 FEB 2014
F	ADDED SECOND ALTERNATE CONSTRUCTION BOTTOM VIEW. REQ. BY K. MUSTAFA.	21 JUL 2015

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